Working Note ARL-96-07

OPP Signal Description

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This document provides the Input and Output signal description, position, and timing for the Output Port Processor (OPP) integrated circuit used in the Washington University Gigabit Switch described in "System Architecture Document for GIGABIT SWITCHING TECHNOLOGY, Version 3.1, Working Note ARL-94-11, by Jonathan S. Turner and staff.



OUTPUT PORT PROCESSOR(OPP) I/O DIAGRAM

Signal Descriptions:

The OPP provides an interface between the ATM port with its associated link clock, and the switch core with its associated core clock. The signaling within the switch core utilizes a clock-to-data deskewing circuit and a high (120mhz) clock rate. The signaling associated with the ATM port is described in great detail in "The Gigabit Switch Link Interface Specification" by W. D. Richard, Version 4.1, Working Note ARL-94-17, Jan. 18, 1996. The ATM port signals will only be listed in this document. The signals associated with the switch core, and the test signals associated with the OPP will be described in this document.

Port Interface Signals: (Described in W. D. Richard)

WIDTH_LINK (Input) A static level, sets port data interface to 16 or 32 bit data word.UNASSIGN_EN (Input) Static level, Enables transmission of Unassigned Cells during idle cell periods.

CLK_LINK (Input) The link "clock".

TCA_LINK (Input) Send another cell enable signal, intended for use with early UTOPIA devices. **TCA_FF_LINK** (Input) Send another cell enable signal. Used for all but early UTOPIA devices.

D_L_OPP <15 . . 0> (Outputs) The link lower 16 data bits.

D_H_OPP <16 . . 31> (Outputs) The link upper 16 data bits.

SOC_L_OPP (Output) The link Start Of Cell signal for the lower 16 data bits.

SOC_H_OPP (Output) The link Start Of Cell signal for the upper 16 data bits.

DAV_L_OPP (Output) The Data AVailable signal for the lower 16 data bits.

DAV_H_OPP (Output) The Data AVailable signal for the upper 16 data bits.

RESET_OPP (Output) A buffered RESET feed that reflects the switch RESET signal. This signal is not synchronized with the link clock (The "CLK_LINK").

PAD_ZERO (Input) Forces a particular pattern (all zeros) into an unused byte(s) of the 16 and 32 bit wide utopia header formats. Needed by some utopia devices. A static level.

Core Signals, OPP to IPP:

D_OPP<31-0> (Output) The OPP data connection to the IPP transmits 32 bits of data labeled 0 through 31. The OPP to IPP connection transmits 32 bits of data each clock period.

- **SOC_OPP** (Output) The Start Of Cell (SOC) signal from the OPP is received by the IPP. This once per cell time signal is aligned with the first word of each cell and is used to synchronize the data communication between the OPP and the IPP.
- **PARI_OPP** (Output) Odd parity over the 32 bit field of the "D_OPP" data. A new parity value is transmitted every clock period.
- CLK_OPP (Output) A clock signal to the IPP that is phased with the data sent to the IPP.

Core Signals, OPP from SE:

- **D**[SE slice number]_SE
bit number> (Input) Each OPP receives a total of 32 bits from the four bit-sliced SE circuits that create one logical "SE" element. The SE slices are labeled 0 through 3, and the eight bits of data from each SE slice are labeled 0 through 7. Each group receives a new eight bit data value each core clock period.
- **CTRL[SE slice number]_SE** (Input) Each OPP receives a total of 4 bits of control from the four bit-sliced SE circuits. Bit 0 is received from SE slice 0, bit 1 is received from SE slice 1, etc. Many of the SE CTRL outputs are not used at the interface to the OPP, but would be used in a multi-stage switch for connection from SE chip to SE chip. A new control value is received

each clock period.

PARI[SE slice number]_SE (Input) Each of the four bit-sliced SE circuits transmits Odd parity over the twelve bit field of the combined "D" (data) and "CTRL" fields delivered from each particular SE circuit. A new parity value is received each clock period.

Global Signals:

CLK (Input) Input clock to the OPP chip.

- **CELL_CLK** (Input) The OPP chip receives a cell clock signal that has a period sixteen times that of the CLK signal. (The form of the CELL_CLK signal period is one CLK clock period high, fifteen clock CLK periods low.) The CELL_CLK signal is the only signal that must meet a setup and hold relationship with every cycle of the CLK signal.
- **RESET** (Input, asserted low) The OPP chip receives a reset signal that must meet a setup and hold time relationship with respect to the CLK transition two CLK cycles before the CLK transition for which CELL_CLK is high. Circuit simulations have shown that the reset signal asserted for 160 clock periods (or more) is adequate for proper circuit operation.
- **CLR_ERR** (Input) The CLR_ERR signal clears all error flags in the switch without halting operation of the switch. The actions of the CLR_ERR signal are a sub-set of the actions of the RESET signal. Any error flag cleared by CLR_ERR is also cleared by RESET. The CLR_ERR signal has the same setup and hold time relationship with the CELL_CLK signal as the RESET signal. Circuit simulations have shown that this signal asserted for 160 clock periods (or more) is adequate for proper circuit operation.
- $C_CLK_TAP < bit number > 1$ (Input) The timing relationship between the CELL_CLK and the received cell data from the core of the switch is set with this four bit field. Circuit simulations have shown that setting these four bits 160 clock periods (or more) prior to the end of the RESET period is adequate for proper circuit operation. The four signals are typically connected to physical switches or jumpers. $CC_TAP = 0000$ (binary) sets the timing relationship between the outgoing cell and the CELL_CLK such that the first word of a cell is received at the input to the OPP chip on the clock period the CELL_CLK is positive. (See the timing diagrams in Figure 3 for a more detailed timing relationship between the data and the CELL_CLK.) $CC_TAP = 0001$ (binary) sets the timing relationship such that the first word of a cell is transmitted one CLK period later, etc.
- **TIME_SYNC** (Input) This signal synchronizes the time stamp value in the OPP and is intended to be used when "hot board swapping" is designed into the Gigabit Switch. When a board with a OPP on it is replaced in an operating system, the value in the OPP time stamp resister must be reset to the same value that is currently in the rest of the OPPs and IPPs in the switch. To accomplish this re-synchronization, the OPP contains a 33 bit shift register circuit. The input to the shift register is the TIME_SYNC signal. The value of the TIME_SYNC signal is shifted in once per cell time, with the same timing relationships used by the reset cell clk signaling. When the 33ed bit of the OPP shift register is a "one" (electrical high), the lower 32 bits are parallel loaded into the 32 bit time stamp register/counter and the 33 bit shift register is cleared. The

^{1.} These signals were included to compensate for an expected non-integer cell propagation time through the SE. Since the cell propagation time is an integer cell time (16 CLK periods) with the present SE design, CC_TAP is set to zero in the present switch.

master source of the TIME_SYNC signal will be in the same set of circuits that provide the clk, cell clk, and reset signals for the gigabit switch. The TIME_SYNC master source is expected to transmit a one cell time wide "one" signal (a "start" bit), followed by the 32 bit current time stamp value as a serial bit stream, at a rate of one bit per cell time. This bit stream can be sent as often as once every 65 cell times. Providing a 32 bit sequence of all "0"s between the end of one serial bit stream and the "start" bit of the next serial bit stream allows a specification that any OPP will have it's time stamp register synchronized with the rest of the gigabit switch system in less than 100 cell times. (The maximum sequence is the OPP comming out of reset and just missing a start bit on a time stamp sequence of all zeros with a LSB being a "1" (32 cell times) plus the 32 bit "dead time" sequence of "0" (32 more cell times) plus the 33 cell time sequence of a correct time stamp. Thus a total of 97 cell times maximum after partial reset is removed is needed to assure all OPPs in a system are synchronized again.)

Test Signals:

BIST_CLK (Input) On-chip memory test clock, tie to ground when not in the memory test mode.
BIST_TEST (Input) On-chip memory test pin. Tie to ground when not in the memory test mode.
TEST_EN (Input) This signal enables the test output pins. When TEST_EN is low, all test output pins will be inactive and low.

TEST_IN<2..0> (Input) Three extra inputs that are specified now so that the PC board layout can be finished. These three inputs will be tied to ground in the PC board layout. TEST_IPP<??..0> (Output). To be defined.

Power Signals:

The OPP chip has a set of 3.3V power pads that supply power to the core of the chip, a set of 3.3V power pads that supply power to the pad I/O circuits, and a 5.0V power pad that is used in conjunction with the TTL input signals for the port interface.

Core PWR 3.3V pads that supply power to the core of the chip.

Periphery PWR 3.3V pads that supply power to the chip pads. (The Periphery of the chip).

- TTL PWR 5.0V pad that provides the input bias voltage for the TTL input pads.
- The OPP chip has a set of ground pads that feed the core of the chip, a set of pads that feed the pads themselves, and a set of ground pads that are used in conjunction with the TTL input signals for the port interface.
- **Core GND** Ground pads that feed the core of the chip.

Periphery GND Ground pads that feed the chip pads themselves. (The Periphery of the chip).

TTL GND TTL input ground pads.

Chip Physical Specifications:

The signal names used in Figure 1 are the same signal names used in the OPP_TOP.pin file that is generated as part of the design flow for each circuit. The OPP_TOP.pin file for the Input Port Processor chip is attached as Appendix A. The OPP_TOP.pin file lists the chip SIGNAL and 5.0V TTL power pads in the order they appear around the edge of the chip (TTL power pads are included with the signal pins since they are not connected to the package power plane as are the other (3.3V core and periphery) power pads). The 3.3V power and all the ground pads are then listed. The "PAD CENTRE COORDINATES" column must be used to determine the interleaving of power and ground pads with the signal pads. The "BND PIN" column of the OPP_TOP.pin file lists the package cavity bonding land number. The SIGNAL and 5.0V TTL power bonding land numbers, numbers 1 through 256, map to the ES2 299 pin PGA package pin designations, "A1" through "X20" (See Appendix B) The 299 PGA package used to house the SE chip has power and ground planes within the package. Thus the 3.3V power and all the ground PINS on the PGA package do not map directly to the power and ground PADS on the chip. As detailed in Appendix B, there are a total of 21 power and 22 ground pins on the package. (Note, from Figure 1, that there are a total of <<XX>> power and <<<YY>> ground PADS on the chip.) The OPP chip layout, Figure 2, indicates the coordinates on the chip which are used with the Table of Appendix A to identify the position of each pad.

7000, 7000

7000, -7000

TO BE ADDED

-7000, 7000

-7000,7000

Figure 2

Output Port Processor with Coordinate System used in Appendix A shown.

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SIGNAL TIMING:

The general timing values and conditions for all three GigaBit Switch chips (SE, IPP, OPP) are given in ARL-96-4. Information specific to the OPP is given here.

INPUT SIGNAL TIMING FROM SE:

The OPP chip input circuits include clock-to-data deskewing circuits which adjust the timing of the data path, relative to the clock, over approximately two clock periods. These circuits significantly increase the traditional signal-timing tolerances.

GENERAL INPUT SIGNAL TIMING:

CLK: up to 120MHz, 40%-60% worst case duty factor, rise and fall times < 2ns. CELL_CLK: setup time > 1.75ns, hold time > 1.00ns

- RESET, CLR_ERR: clocked on the positive clock transition two transitions before the transition for which the CELL_CLK signal is high. Detailed timing is shown in Figure 4.
- D_SE, CTRL_SE, and PARI_SE: The general timing, including the relationship between the ATM cell word position relative to CELL_CLK and the value of CC_TAP, is shown in Figure 3. The D_SE, CTRL_SE, and PARI_SE in the data groups indicated below. Detailed timing shown in Figure 3.

Group 1, Dx_SE_0 through Dx_SE_4 (5 bits) -- all relative to Dx_SE_0

Group 2, Dx_SE_5 through Dx_SE_7, CTRLx_SE, and PARIx_SE (5 bits) -all relative to Dx_SE_5 (Note: this grouping may change.)

OUTPUT SIGNAL TIMING

Detailed timing is shown in Figure 3. The timing details of the output signals associated with the link interface are described in W. Richard.





Appendix A

(Print out of the pin_package_rpt_APPENDIX_A.txt file, this directory) (pages A-1 through A-10)

Until the OPP layout is finished, there is no pin_package_rpt_APPENDIX_A.txt file. Until then, the following table can serve to guide planning for the OPP. The table is designed to show the defined paths between the OPP chip pads, and 299 PGA package bonding lands. This information allows the designer to KNOW the sequence of the signal pads around the OPP chip, to KNOW which of the four edges a particular signal pad is placed, and to ESTIMATE approximately where along a chip edge a particular signal pad is placed based on the knowledge of the placement of the attaching bonding land in the package.(see Appendix B) The power and ground pads are less well defined. The sequential placement and number of the power and grounds in the following table are approximate and *will* be changed as the OPP layout progresses. The PGA package being used has regions of power bonding lands, and regions of ground bonding lands so that a ground or a power pad placed anywhere adjacent to a region can still be bonded to the package power or ground bonding land. It is possible that, late in the OPP chip layout process, the positions of a power or a ground pad will be moved, one way or the other, past a few signal pads. (Note, the 5 Volt power connections to the chip use package signal pins and thus can not move past other signal pads Only the +3.3 volt and ground pads may move within the regions.) Thus the only way to assure the designed OPP chip will match a new package bonding land pattern is to provide a three-tier bonding land system with two of the tiers being a power ring and a ground ring and the third tier being all the signal connections in the proper sequence and chip edge, or to make an exact physical copy of the targeted two tier PGA package chip cavity. It should be noted that the placement of the test output pads is not included. (The INPUT test pad locations are included.) The number and function of the test output pads is adjusted based design details of each block. Thus the final test pad list is not known until late in the design cycle. The output test pad placements are not critical to chip attachment designs as all output test pads could be left unconnected. Each two pages of the following table covers one edge of the OPP chip: (The four "CRNGNDPY" type pads are the pads that fit in the four corners of the pad ring.)



Signal Name	Package Pin	Bonding land	pad type
GND	_	273	CRNGNDPY(Corner)
GND (GNDCO_P_1)	-	273	GNDCO Chip
GND (GNDPY_P_1)	-	273	GNDPY edge
D3_SE<3>	C3	1	IPS8B 1
> not connected <	E5	2	{NO pad}
D3_SE<2>	В3	3	IPS8B
> un-used <	E6	4	<space></space>
D3_SE<5>	C4	5	IPS8B
RSQ_EMP	D6	6	OPS0T
RSQOVF	D5	7	OPSOT
> un-used <	E7	8	<space></space>
D3_SE<4>	В4	9	IPS8B
PARI3_SE	C5	10	IPS8B
Vdd (+3.3V) (PWRCO_P_1)	-	274	PWRCO
CTRL3_SE	B5	11	IPS8B
Vdd (+3.3V) (PWRPY_P_1)	-	274	PWRPY
D3_SE<6>	A5	12	IPS8B
Vdd (+3.3V) (PWRCO_P_2)	-	274	PWRCO
> un-used <	C6	13	<space></space>
Vdd (+3.3V) (PWRPY_P_2)	-	274	PWRPY
D2_SE<0>	вб	14	IPS8B
Vdd (+3.3V) (PWRCO_P_3)	-	274	PWRCO
> un-used <	D7	15	<space></space>
Vdd (+3.3V) (PWRPY_P_3)	-	274	PWRPY
NO_BOND_GNDCO_2			GNDCO
D3_SE<7>	A6	16	IPS8B
GND (GNDCO_P_2)	-	258	GNDCO
GND (GNDPY_P_2)	-	258	GNDPY
> un-used <	C7	17	<space></space>
> un-used <	E8	18	<space></space>
D2_SE<2>	в7	19	IPS8B
> un-used <	D8	20	<space></space>
D2_SE<1>	A7	21	IPS8B
> un-used <	E9	22	<space></space>
D2_SE<5>	C8	23	IPS8B
> un-used <	D9	24	<space></space>
D2_SE<3>	B8	25	IPS8B
D2_SE<7>	C9	26	IPS8B
D2_SE<4>	A8	27	IPS8B
CTRL2_SE	C10	28	IPS8B
D2_SE<6>	В9	29	IPS8B
> un-used <	E10	30	<space></space>
PARI2_SE	B10	31	IPS8B
> un-used <	D10	32	<space></space>
GND (GNDPY_P_3)	-	259	GNDPY
GND (GNDPY_P_4)	-	259	GNDPY
$Vdd (+3.3V) (PWRPY_P_4)$	-	275	PWRPY
Vdd $(+3.3V)$ (PWRCO_P_4)	-	275	PWRCO
Vdd (+3.3V) (PWRPY_P_5)	-	275	PWRPY

Signal Name	Package Pin	Bonding land	pad type	
D1 SE<0>		33	TPS8B	
	בבם 11ת	34	<gpage></gpage>	
D1 SE<2>	B12	35	TDC8B	
	F11	36	<gpage></gpage>	
$rac{1}{2}$	D13	37		
DI_3E<4/	C11	20	TLCOD	
DI_3E <i <="" td=""><td>Δ11 λ11</td><td>20</td><td>TLCOD</td><td></td></i>	Δ11 λ11	20	TLCOD	
DI_SE	A14 010	39	TLOOD	
DI_SE <s></s>		40	TP20B	
DI_SE<5>		4⊥ 40	TPS8B	
> un-usea <	DIZ D14	42	<space></space>	
DI_SE<0>	B14 D10	43	TPS8B	
> un-used <	ELZ 215	44	<space></space>	
DU_SE<1>	AL5	45	TD28B	
> un-used <	DI3	46	<space></space>	
NOT_RDY	ET 3	48	OPS0T	
PARII_SE	C14	4'/	IPS8B	
CTRL1_SE	B15	49	IPS8B	
GND (GNDPY_P_5)	-	260	GNDPY	
GND (GNDCO_P_3)	-	260	GNDCO	
D0_SE<2>	A16	50	IPS8B	
Vdd (+3.3V) (PWRPY_P_6)	-	276	PWRPY	
> un-used <	C15	51	<space></space>	
$Vdd (+3.3V) (PWRCO_P_5)$	-	276	PWRCO	
D0_SE<0>	B16	52	IPS8B	
Vdd (+3.3V) (PWRPY_P_7)	-	276	PWRPY	
D0_SE<5>	A17	53	IPS8B	
Vdd (+3.3V) (PWRCO_P_6)	-	276	PWRCO	
> un-used <	C16	54	<space></space>	
Vdd (+3.3V) (PWRPY_P_8)	-	276	PWRPY	
D0_SE<4>	B17	55	IPS8B	
> un-used <	D16	56	<space></space>	
> un-used <	D14	57	<space></space>	
D0 SE<3>	C17	58	IPS8B	
> un-used <	E14	59	<space></space>	▲
D0 SE<7>	B18	60	IPS8B	
> un-used <	D15	61	<space></space>	
CTRLO SE	B19	62	IPS8B	
> un-used <	E15	63	<space></space>	
> not connected <	 17	64	{No pad}	chip
GND (GNDPY P 6)		261	GNDPY	edae
GND (GNDCO_P_4)	_	261	GNDCO	1

Signal Name	Package Pin	Bonding land	pad type
GND	_	261	CRNGNDPY(corner)
GND (GNDCO_P_5)	-	261	GNDCO chip
GND (GNDPY_P_7)	-	261	GNDPY edge
D0_SE<6>	C18	65	IPS8B
> not connected <	E16	66	{No pad}
PARIO_SE	C19	67	IPS8B
UP_DISC_P	F16	68	OPSOT
> un-used <	D18	69	<space></space>
> un-used <	F17	70	<space></space>
> un-used <	E17	71	<space></space>
D_OPP<0>	G16	72	OPSOT
> un-used <	D19	73	<space></space>
> un-used <	E18	74	<space></space>
Vdd (+3.3V) (PWRPY_P_9)	-	277	PWRPY
> un-used <	D20	75	<space></space>
Vdd (+3.3V) (PWRCO_P_7)	-	277	PWRCO
> un-used <	E19	76	<space></space>
Vdd (+3.3V) (PWRPY_P_10)	-	277	PWRPY
> un-used <	F.T.8	77	<space></space>
Vdd (+3.3V) (PWRCO_P_8)	-	277	PWRCO
> un-used $<$	EZU	/8	<space></space>
Vad (+3.3V) (PWRPY_P_II)	-	277	PWRP1
$D_{OPP<1>}$	GT /	19	OPSUT CNDCO
$(GINDCO_P_0)$	_	202	CNDDY
		202	CNDCO
> un-used <	F19	80	<space></space>
D OPP<5>	н16	81	OPSOT
D OPP<2>	G18	82	OPSOT
D OPP<6>	H17	83	OPSOT
CLK OPP	F20	84	OPSOT
D OPP<9>	J16	85	OPS0T
D OPP<3>	G19	86	OPS0T
D_OPP<10>	J17	87	OPS0T
D_0PP<7>	H18	88	OPSOT
D_0PP<11>	J18	89	OPSOT
D_OPP<4>	G20	90	OPS0T
D_OPP<15>	K18	91	OPS0T
D_OPP<8>	Н19	92	OPS0T
D_OPP<13>	K16	93	OPS0T
D_OPP<12>	J19	94	OPS0T
D_OPP<14>	K17	95	OPS0T
D_OPP<16>	К19	96	OPS0T
Vdd (+3.3V) (PWRPY_P_12)	-	278	PWRPY
Vdd (+3.3V) (PWRCO_P_9)	-	278	PWRCO
Vdd (+3.3V) (PWRPY_P_13)	-	278	PWRPY
GND (GNDPY_P_9)	-	263	GNDPY
GND (GNDCO_P_18)	-	263	GNDCO

Signal Name	Package Pin	Bonding land	pad type	
D_OPP<18>	L17	97	OPSOT	
D_OPP<20>	L19	98	OPSOT	
D_OPP<17>	L16	99	OPSOT	
D_OPP<24>	M19	100	OPSOT	
D_OPP<19>	L18	101	OPSOT	
L_XFRM	N20	102	OPSOT	
D_OPP<23>	M18	103	OPSOT	
D_OPP<28>	N19	104	OPSOT	
D OPP<22>	M17	105	OPSOT	
SOC OPP	P20	106	OPSOT	
D OPP<21>	M16	107	OPSOT	
D_OPP<27>	N18	108	OPSOT	
D OPP<26>	N17	109	OPSOT	
PARI OPP	P19	110	OPSOT	
D OPP<25>	N16	111	OPSOT	
R XFRM	R20	112	OPSOT	
GND (GNDPY P 11)	_	264	GNDPY	
(ODCOP7)	_	264	GNDCO	
$D \cap PP < 31 >$	P18	113	OPSOT	
Vdd (+3 3V) (PWRCO P 10)	-	279	PWRCO	
	R19	114	OPSOT	
Vdd (+3.3V) (PWRPY P 14)	-	279	DWRDY	
-2 un-used $<$	ጥ20	115	<gnace></gnace>	
Vdd (+3 3V) (PWRCO P 11)	-	279	PWRCO	
> un-used <	P18	116	<pre>canada></pre>	
Vdd (+3.3V) (DWPDV D 15)	-	279	DWPDV	
(15.5) (FWRFI_F_I5)	·π1 Q	117		
Vdd (+2.3V) (DWDCO D 12)	119	270		
$(+3.3)$ (PWRCO_P_12)	- TT20	110	FWRCO	
16	020			
Vad (+5.5V) (PWRPI_P_10)	- m1 0	110	PWRPI	
> un-used <		120	<space></space>	
> un-used <	019 D17	120 121	<space></space>	
D_OPP<30>	P17		OPSUI	
	T1 /	122	OPSUT	
D_OPP<29>	PI6	123	OPSUT OPSUT	
EMPT_CSTR_T	UI8	124	OPS01	
> un-used <	RT.1	125	<space></space>	1
RESET_OPP(RES_OPP_P)	V19	126	OPSIT	
> un-used <	R16	127	<space></space>	
D_H_OPP<15>	V18	128	OPSIT	chip
GND (GNDPY_P_12)	-	265	GNDPY	edge
GND (GNDCO_P_8)	-	265	GNDCO	2

Signal Name	Package Pin	Bonding land	pad type
GND GND (GNDCO_P_9) GND (GNDCO P 10)	 _ _	265 265 265	CRNGNDPY(corner) GNDCO chip GNDCO edge
GND (GNDPY_P_13) > not connected < > not connected <	- U17 T16	265 129 130	GNDPY 3 {no pad} {no pad}
> un-used < > un-used < D_H_OPP<12>	W19 T15 W18 U15	131 132 133 134	<space> <space> OPS1T</space></space>
D_H_OPP<14> C_CLK_TAP<3> > un-used <	V17 T14 U16	134 135 136 137	<pre> OPS1T IPS8B <space></space></pre>
D_H_OPP<13> Vdd (+3.3V) (PWRPY_P_17) D_H_OPP<11>	W17 - V16	138 280 139	OPS1T PWRPY OPS1T
Vdd (+3.3V) (PWRCO_P_13) D_H_OPP<10> Vdd (+3.3V) (PWRPY_P_18)	- W16 -	280 140 280	PWRCO OPS1T PWRPY ODS1T
Vdd (+3.3V) (PWRCO_P_14) D_H_OPP<6> Vdd (+3.3V) (PWRPY P 19)	- V15 -	280 142 280	PWRCO OPS1T PWRPY
D_H_OPP<7> GND (GNDCO_P_11) GND (GNDPY_P_14)	W15 - -	143 266 266	OPS1T GNDCO GNDPY
NO_BOND_GNDCO_4 > un-used < C_CLK_TAP<2>	U14 T13	144 145	GNDCO <space> IPS8B</space>
D_H_OPP<8> > un-used < D_H_OPP<5> C CLK TAP<1>	U13 V14 T12	140 147 148 149	<pre> <space> OPS1T IPS8B </space></pre>
D_H_OPP<3> > un-used < D_H_OPP<4>	W14 U12 X14	150 151 152	OPS1T <space> OPS1T</space>
SOC_H_OPP D_H_OPP<1> > un-used <	V12 V13 V11 W12	153 154 155	OPS1T OPS1T <space> OPS1T</space>
C_CLK_TAP<0> > un-used < > un-used <	T11 X13 U11	157 158 159	IPS8B <space> <space></space></space>
D_H_OPP<0> Vdd (+3.3V) (PWRPY_P_20) Vdd (+3.3V) (PWRCO_P_15)	W12 - -	160 281 281	OPS1T PWRPY PWRCO DWDDW
NO_BOND_PWRCO_2 GND (GNDCO_P_14) GND (GNDPY_P_16)	_	267 267	PWRCO GNDCO GNDPY

Signal Name	Package Pin	Bonding land	pad type	
D. J. ODD (12)		1.61	0001	
D_L_OPP<13>		161	OPSIT ODG1T	
	WII TIO	162	UPSII	
D I ODC15	110 W10	164		
$D_1 OPP < 14$	W10	165		
$D_1 OPP < 12>$	W9	166	OPS1T	
$D_1 OPP < 11 >$	V9	167	OPS1T	
$D_1 OPP < 10 >$	W8	168	OPS1T	
TIME SYNC(T SYNC)	U9	169	IPS8B	
D L OPP<8>	X7	170	OPS1T	
RESET	Т9	171	IPS8B	
D_L_OPP<9>	V8	172	OPS1T	
> un-used <	U8	173	<space></space>	
D_L_OPP<7>	W7	174	OPS1T	
CELL_CLK	Т8	175	IPS8B	
D_L_OPP<5>	Хб	176	OPS1T	
GND (GNDCO_P_12)	-	268	GNDCO	
GND (GNDPY_P_17)	-	268	GNDPY	
D_L_OPP<6>	V7	177	OPS1T	
NO_BOND_GNDCO_5			GNDCO	
Vdd (+3.3V) (PWRPY_P_22)	-	282	PWRPY	
D_L_OPP<4>	W6	178	OPS1T	
Vdd (+3.3V) (PWRCO_P_16)	-	282	PWRCO	
$D_L_OPP<2>$	X5	179	OPSIT	
Vaa $(+3.3V)$ (PWRPY_P_23)	-	282	PWRPY ODG1m	
$D_L_OPP<3>$	VO	180	DWDCO	
Val $(+3.3V)$ (PWRCO_P_17) D I ODD (-1)	- W5	202 101	PWRCU ODC1T	
U_{-1} U_{-2} U_{-1} U	WD	101 202	OPSII	
POC I. OPD	- 	182	ODS1T	
Vdd (+3 3V) (PWRCO P 18)	-	282	DWRCO	
D I OPP < 0 >	W 5	183	OPS1T	
-> un-used <	¥9 W4	184	<space></space>	
> un-used <	U7	185	<space></space>	
> un-used <	U5	186	<space></space>	
CLK(C P)	т7	187	IPS8B	▲
DAV L OPP	V4	188	OPS1T	
un-used <	UG	189	<space></space>	
> un-used <	W3	190	<space></space>	
> un-used <	Тб	191	<space></space>	•
> not connected <	V3	192	$\{\bar{\texttt{No} pad}\}$	chip
GND (GNDPY_P_18)	-	269	GNDPY	edge
GND (GNDCO_P_13)	-	269	GNDCO	3

Signal Name	Package Pin	Bonding land	pad type
GND	_	269	CRNGNDPY(Corner)
> No bond land needed <	_	_	MISOPYR chip
GND (MGNDCO_P_1)	_	269	MGNDCO edge
GND (MGNDPY_P_1)	-	269	MGNDPY
> not connected <	U4	193	{No pad}
WIDTH_LINK	Т5	194	MIPS8G
> un-used <	W2	195	<space></space>
TCA_LINK	R5	196	MIPS8G
PAD_ZERO(P_ZERO)	V2	197	MIPS8G
TCA_FF_LINK	R4	198	MIPS8G
Vcc(+5V) (MPWRPY_P_1)	U3	199	MPWRPY
UNASSIGN_EN(UN_EN_P)	P5	200	MIPS8G
CLK_LINK	Τ4	201	MIPS8G
> No bond land needed <	-	-	MIPSOPYL
FSL_LEN_P_0	02	202	OPSUT
Vdd (+3.3V) (PWRCO_P_19)	-	283	PWRCO
$FSL_LEN_P_I$.1.3	203	OPSUT DVDDV
$Vaa (+3.3V) (PWRPY_P_25)$	- TT1	283	PWRPY
$F_{DL} = M_{2} = 2$	UL	204	DWDGO
VUL $(+3.3V)$ (PWRCU_P_2U) EST LEN D 2	- TTO	203	
Vdd (+3 3V) (DWRCO D 21)	12	205	DWRCO
FOL LEN D 4	ΡŻ	205	
Vdd (+3 3V) (PWRCO P 22)	-	283	PWRCO
FSI, LEN P 5	т1	203	OPSOT
Vdd (+3.3V) (PWRPY P 27)	_	283	PWRPY
FSL LEN P 6	P4	208	OPSOT
GND (GND PY 21)	_	270	GNDPY
GND (GNDCO_P_15)	_	270	GNDCO
FSL_LEN_P_7	R2	209	OPSOT
TLDC_P	N5	210	OPSOT
CS1_OCC_P_7	P3	211	OPSOT
CS1_OCC_P_6	N4	212	OPSOT
CS1_OCC_P_5	R1	213	OPSOT
CS1_OCC_P_4	M5	214	OPSOT
CS1_OCC_P_3	P2	215	OPSOT
CS1_OCC_P_2	M4	216	OPSUT
CSI_OCC_P_I	N3	217	OPSOT
CSI_OCC_P_U	M3	218	OPSUT ODGOW
	PI T 2	219	OPSUT OPSUT
	Ц3 NO	220	OPSUI ODSUT
$CSU_OCC_P_S$	IN Z	221	
$CSU_OCC_P_4$	ШЭ М2	222	
$CSO_OCC_F_S$	п.2	223	
GND (GND PY 22)	_ _	271	GNDPY
GND (GNDCO P 16)	_	271	GNDCO
Vdd (+3.3V) (PWRPY P 28)	_	284	PWRPY
Vdd (+3.3V) (PWRCO P 26)	_	284	PWRCO
Vdd (+3.3V) (PWRCO_P_25)	-	284	PWRCO

Signal Name	Package Pin	Bonding land	pad type	
CSO OCC P 1	L2	225	OPS0T	
CSO OCC P O	к4	226	OPSOT	
TEST EN	к2	227	TPS8B	
> un-used <	К5	228	<space></space>	
[missing]TEST IN2	л2	229	TPS8B	
[missing]TEST_IN1	к3	230	TPS8B	
-> un-used $<$	H1	231	<space></space>	
[missing]TEST IN()	<u>т</u> 3	232	TPS8B	
BIST CLK	н2	233	TPS8B	
> un-used <	 J4	234	<space></space>	
BIST TEST	H3	235	IPS8B	
BIST RESO	J5	236	OPSOT	
BIST RES1	Gl	237	OPSOT	
BIST RES2	H4	238	OPSOT	
> un-used <	G2	239	<space></space>	
> un-used <	Н5	240	<space></space>	
> un-used <	G3	241	<space></space>	
GND (GNDCO_P_17)	_	272	GNDCO	
GND (GNDPY_P_19)	-	272	GNDPY	
> un-used <	F1	242	<space></space>	
Vdd (+3.3V) (PWRCO_P_24)	-	285	PWRCO	
> un-used <	F2	243	<space></space>	
Vdd (+3.3V) (PWRCO_P_29)	-	285	PWRCO	
NO_BOND_GNDCO_3			GNDCO	
NO_BOND_PWRCO_1			PWRCO	
> un-used <	F3	244	<space></space>	
Vdd $(+3.3V)$ (PWRCO_P_27)	-	285	PWRCO	
> un-used <	El	245	<space></space>	
Vdd $(+3.3V)$ (PWRPY_P_26)	-	285	PWRPY	
> un-used <	E2	246	<space></space>	
> un-used <	E3	247	<space></space>	
> un-used <	G4 D2	248	<space></space>	
> un-used <	D2	249	<space></space>	
> un-used <	G5	250	<space></space>	
> un-used <	D3	251	<space></space>	•
> un-used <	F'4	252	<space></space>	
D2_SE <t></t>		∠53 254	TRZAR	
> un-usea <	比4 D2	254 255	<space></space>	
	BZ EE	200 256	THOOR	ah i
> un-used $<$	F D D4	200 257	<space></space>	curb
GND (GNDCO_P_19)	D4 -	273	GNDCO	eage 4

Appendix B

(Copy of 299 PGA pin out from data book) (A single page, page 35 of data book)

Appendix C

(Copy of Bonding Diagrams Submitted to Atmel/ES2) (4 pages)

The package used for the OPP chip is a 299 pin PGA package with an internal power and ground plane. The use of the power and ground planes in the package force a fixed package pin assignment for the package power and ground outside pins. Inside the bond cavity, the power and the ground planes each appear as fixed location bond land regions around the bond cavity. These bonding regions vary in size from an area large enough to support bonds to seven power or ground chip pads, to an area the same size as the signal bonding lands. Also, the placement of a power or ground pad around any part of the periphery of the chip that is not lined up with the appropriate power or ground region can not be effectively fed from the package. The inductance of a signal pin circuit is so much higher than the inductance of a power or ground plane connection circuit that there is little value in making a power or ground connection using a signal pin circuit. However, to effectively feed the core circuit from the pad ring power, it is often helpful to place a power or ground pad in the pad ring and use this pad to only feed power to the core. Thus chip designs end up with power and ground pads that are not intended to be bonded. The Atmel/ES2 software tool set does not support this package very well. Thus there is some hand drawn work required to complete the bonding diagrams. To assure there are no errors in the hand drawn work, there are four pages of bonding diagrams.

The four pages of bonding diagrams are attached as this Appendix C. The first page details the extent of the hand work, and points out the core power feed pads on the chip that do not receive bond wires. The second page shows all the bonds on one diagram. Page two is a repeat of page one without all the notes. The package cavity is a two tier design. The bond connections to just the bottom(inside) tier is shown on the third page, and the bonds to just the top (outer) tier is shown on page four.

TO BE ADDED

ADDITIONS, Version 0.2

- Signal CLK_OPP was added sometime. Not sure this signal was in the Aug, '96 version.
- BIST_TEST and BIST_CLK were added sometime. Not sure these signals were in the Aug. '96 version.
- added TIME_SYNC and PAD_ZERO signals
- Changed QUICK_TEST3 to TEST_EN
- Changed QUICK_TEST< 2 . .0 > to TEST_IN < 2 . . 0 >